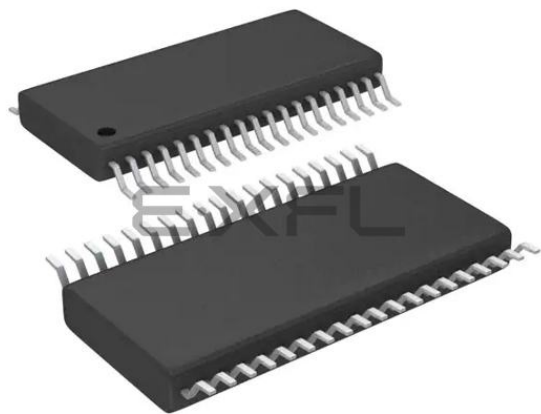




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Details

Product Status	Obsolete
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I ² C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, I ² S, POR, PWM, WDT
Number of I/O	26
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	38-TFSOP (0.173", 4.40mm Width)
Supplier Device Package	PG-TSSOP-38-9
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xmc1302t038x0016aaxuma1

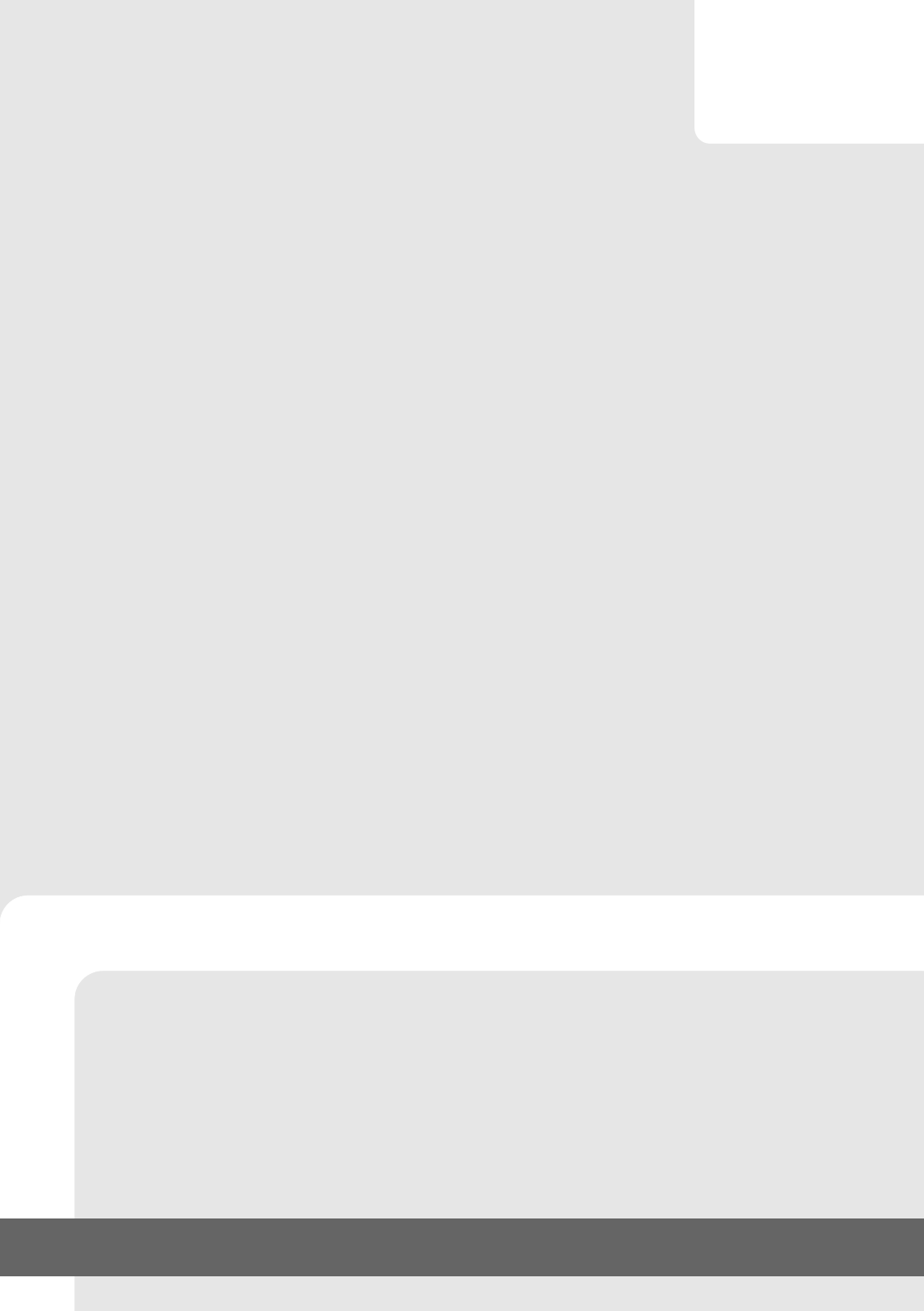


Table of Contents

1	Summary of Features	8
1.1	Ordering Information	10
1.2	Device Types	10
1.3	Device Type Features	11
1.4	Chip Identification Number	12
2	General Device Information	15
2.1	Logic Symbols	15
2.2	Pin Configuration and Definition	17
2.2.1	Package Pin Summary	20
2.2.2	Port I/O Functions	23
3	Electrical Parameter	26
3.1	General Parameters	26
3.1.1	Parameter Interpretation	26
3.1.2	Absolute Maximum Ratings	27
3.1.3	Operating Conditions	28
3.2	DC Parameters	29
3.2.1	Input/Output Characteristics	29
3.2.2	Analog to Digital Converters (ADC)	32
3.2.3	Out of Range Comparator (ORC) Characteristics	36
3.2.4	Analog Comparator Characteristics	37
3.2.5	Temperature Sensor Characteristics	38
3.2.6	Power Supply Current	39
3.2.7	Flash Memory Parameters	41
3.3	AC Parameters	42
3.3.1	Testing Waveforms	42
3.3.2	Output Rise/Fall Times	43
3.3.3	Power-Up and Supply Threshold Characteristics	44
3.3.4	On-Chip Oscillator Characteristics	46
3.3.5	Serial Wire Debug Port (SW-DP) Timing	48
3.3.6	SPD Timing Requirements	49
3.3.7	Peripheral Timings	50
3.3.7.1	Synchronous Serial Interface (USIC SSC) Timing	50
3.3.7.2	Inter-IC (IIC) Interface Timing	53
3.3.7.3	Inter-IC Sound (IIS) Interface Timing	55
4	Package and Reliability	57
4.1	Package Parameters	57
4.1.1	Thermal Considerations	57
4.2	Package Outlines	59

5	Quality Declaration	63
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About this Document

This Data Sheet is addressed to embedded hardware and software developers. It provides the reader with detailed descriptions about the ordering designations, available features, electrical and physical characteristics of the XMC1300 series devices.

The document describes the characteristics of a superset of the XMC1300 series devices. For simplicity, the various device types are referred to by the collective term XMC1300 throughout this document.

XMC1000 Family User Documentation

The set of user documentation includes:

- **Reference Manual**
 - describes the functionality of the superset of devices.
- **Data Sheets**
 - list the complete ordering designations, available features and electrical characteristics of derivative devices.
- **Errata Sheets**
 - list deviations from the specifications given in the related Reference Manual or Data Sheets. Errata Sheets are provided for the superset of devices.

Attention: Please consult all parts of the documentation set to attain consolidated knowledge about your device.

Application related guidance is provided by **Users Guides** and **Application Notes**.

Please refer to <http://www.infineon.com/xmc1000> to get access to the latest versions of those documents.

Table 4 XMC1300 Chip Identification Number

Derivative	Value	Marking
XMC1301-T016F0008	00013032 01CF00FF 00001FF7 0000100F 00000B00 00001000 00003000 101ED083 _H	AA
XMC1301-T016F0016	00013032 01CF00FF 00001FF7 0000100F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1301-T016X0008	00013033 01CF00FF 00001FF7 0000100F 00000B00 00001000 00003000 101ED083 _H	AA
XMC1301-T016X0016	00013033 01CF00FF 00001FF7 0000100F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1302-T016X0008	00013033 01FF00FF 00001FF7 0000900F 00000B00 00001000 00003000 101ED083 _H	AA
XMC1302-T016X0016	00013033 01FF00FF 00001FF7 0000900F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1302-T016X0032	00013033 01FF00FF 00001FF7 0000900F 00000B00 00001000 00009000 101ED083 _H	AA
XMC1301-T038F0008	00013012 01CF00FF 00001FF7 0000100F 00000B00 00001000 00003000 101ED083 _H	AA
XMC1301-T038F0016	00013012 01CF00FF 00001FF7 0000100F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1301-T038F0032	00013012 01CF00FF 00001FF7 0000100F 00000B00 00001000 00009000 101ED083 _H	AA
XMC1302-T038X0016	00013013 01FF00FF 00001FF7 0000900F 00000B00 00001000 00005000 101ED083 _H	AA
XMC1302-T038X0032	00013013 01FF00FF 00001FF7 0000900F 00000B00 00001000 00009000 101ED083 _H	AA
XMC1302-T038X0064	00013013 01FF00FF 00001FF7 0000900F 00000B00 00001000 00011000 101ED083 _H	AA
XMC1302-T038X0128	00013013 01FF00FF 00001FF7 0000900F 00000B00 00001000 00021000 101ED083 _H	AA
XMC1302-T038X0200	00013013 01FF00FF 00001FF7 0000900F 00000B00 00001000 00033000 101ED083 _H	AA
XMC1301-Q024F0008	00013062 01CF00FF 00001FF7 0000100F 00000B00 00001000 00003000 101ED083 _H	AA
XMC1301-Q024F0016	00013062 01CF00FF 00001FF7 0000100F 00000B00 00001000 00005000 101ED083 _H	AA

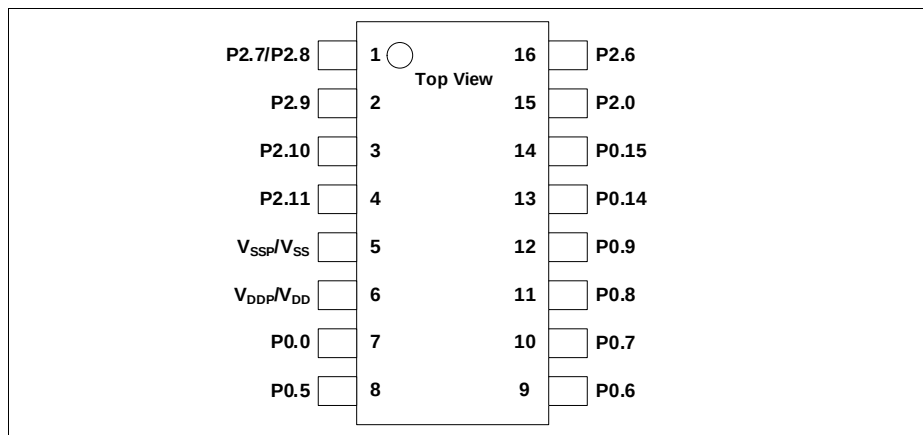


Figure 5 XMC1300 PG-TSSOP-16 Pin Configuration (top view)

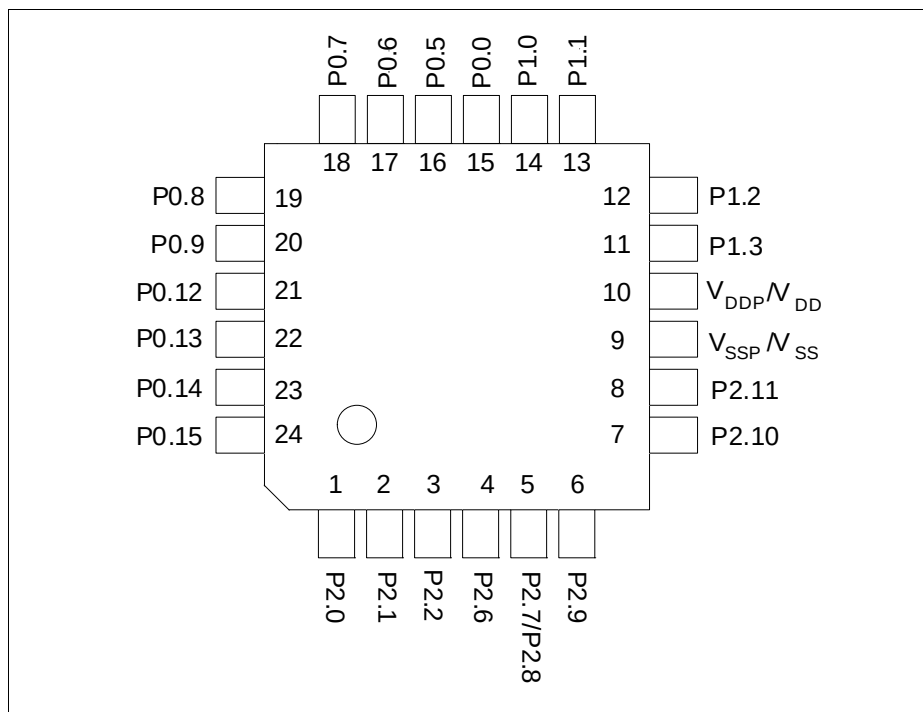


Figure 6 XMC1300 PG-VQFN-24 Pin Configuration (top view)

2.2.1 Package Pin Summary

The following general building block is used to describe each pin:

Table 5 Package Pin Mapping Description

Function	Package A	Package B	...	Pad Type
Px.y	N	N		Pad Class

The table is sorted by the "Function" column, starting with the regular Port pins (Px.y), followed by the supply pins.

The following columns, titled with the supported package variants, lists the package pin number to which the respective function is mapped in that package.

The "Pad Type" indicates the employed pad type:

- STD_INOUT(standard bi-directional pads)
- STD_INOUT/AN (standard bi-directional pads with analog input)
- High Current (high current bi-directional pads)
- STD_IN/AN (standard input pads with analog input)
- Power (power supply)

Details about the pad properties are defined in the Electrical Parameters.

Table 6 Package Pin Mapping

Function	VQFN 40	TSSOP 38	VQFN 24	TSSOP 16	Pad Type	Notes
P0.0	23	17	15	7	STD_INOUT	
P0.1	24	18	-	-	STD_INOUT	
P0.2	25	19	-	-	STD_INOUT	
P0.3	26	20	-	-	STD_INOUT	
P0.4	27	21	-	-	STD_INOUT	
P0.5	28	22	16	8	STD_INOUT	
P0.6	29	23	17	9	STD_INOUT	
P0.7	30	24	18	10	STD_INOUT	
P0.8	33	27	19	11	STD_INOUT	
P0.9	34	28	20	12	STD_INOUT	
P0.10	35	29	-	-	STD_INOUT	
P0.11	36	30	-	-	STD_INOUT	
P0.12	37	31	21	-	STD_INOUT	

2.2.2 Port I/O Functions

The following general building block is used to describe each PORT pin:

Table 7 Port I/O Function Description

Function	Outputs			Inputs		
	ALT1	ALTn	HWO0	HWI0	Input	Input
P0.0		MODA.OUT	MODB.OUT	MODB.INA	MODC.INA	
Pn.y	MODA.OUT				MODA.INA	MODC.INB

Pn.y is the port pin name, defining the control and data bits/registers associated with it. As GPIO, the port is under software control. Its input value is read via Pn_IN.y, Pn_OUT defines the output value.

Up to seven alternate output functions (ALT1/2/3/4/5/6/7) can be mapped to a single port pin, selected by Pn_IOC.R.PC. The output value is directly driven by the respective module, with the pin characteristics controlled by the port registers (within the limits of the connected pad).

The port pin input can be connected to multiple peripherals. Most peripherals have an input multiplexer to select between different possible input sources.

The input path is also active while the pin is configured as output. This allows to feedback an output to on-chip resources without wasting an additional external pin.

By Pn_HWSEL, it is possible to select between different hardware “masters” (HWO0/HWI0, HWO1/HWI1). The selected peripheral can take control of the pin(s). Hardware control overrules settings in the respective port pin registers.

Electrical Parameter
Table 11 Input/Output Characteristics (Operating Conditions apply) (cont'd)

Parameter	Symbol		Limit Values		Unit	Test Conditions
			Min.	Max.		
Input high voltage on port pins (Large Hysteresis)	V_{IHPL}	SR	$0.85 \times V_{DDP}$	—	V	CMOS Mode (5 V, 3.3 V & 2.2 V) ³⁾
Input Hysteresis ¹⁾	HYS	CC	$0.08 \times V_{DDP}$	—	V	CMOS Mode (5 V), Standard Hysteresis
			$0.03 \times V_{DDP}$	—	V	CMOS Mode (3.3 V), Standard Hysteresis
			$0.02 \times V_{DDP}$	—	V	CMOS Mode (2.2 V), Standard Hysteresis
			$0.5 \times V_{DDP}$	$0.75 \times V_{DDP}$	V	CMOS Mode(5 V), Large Hysteresis
			$0.4 \times V_{DDP}$	$0.75 \times V_{DDP}$	V	CMOS Mode(3.3 V), Large Hysteresis
			$0.2 \times V_{DDP}$	$0.65 \times V_{DDP}$	V	CMOS Mode(2.2 V), Large Hysteresis
Pull-up resistor on port pins	R_{PUP}	CC	20	50	kohm	$V_{IN} = V_{SSP}$
Pull-down resistor on port pins	R_{PDP}	CC	20	50	kohm	$V_{IN} = V_{DDP}$
Input leakage current ²⁾	I_{OZP}	CC	-1	1	μA	$0 < V_{IN} < V_{DDP}$, $T_A \leq 105^\circ\text{C}$
Overload current on any pin	I_{OVP}	SR	-5	5	mA	
Absolute sum of overload currents	$\Sigma I_{OV} $	SR	—	25	mA	³⁾
Voltage on any pin during V_{DDP} power off	V_{PO}	SR	—	0.3	V	⁴⁾
Maximum current per pin (excluding P1, V_{DDP} and V_{SS})	I_{MP}	SR	-10	11	mA	—
Maximum current per high current pins	I_{MP1A}	SR	-10	50	mA	—

Table 11 Input/Output Characteristics (Operating Conditions apply) (cont'd)

Parameter	Symbol		Limit Values		Unit	Test Conditions
			Min.	Max.		
Maximum current into V_{DDP} (TSSOP16, VQFN24)	I_{MVDD1}	SR	–	130	mA	³⁾
Maximum current into V_{DDP} (TSSOP38, VQFN40)	I_{MVDD2}	SR	–	260	mA	³⁾
Maximum current out of V_{SS} (TSSOP16, VQFN24)	I_{MVSS1}	SR	–	130	mA	³⁾
Maximum current out of V_{SS} (TSSOP38, VQFN40)	I_{MVSS2}	SR	–	260	mA	³⁾

- 1) Not subject to production test, verified by design/characterization. Hysteresis is implemented to avoid meta stable states and switching due to internal ground bounce. It cannot be guaranteed that it suppresses switching due to external system noise.
- 2) An additional error current (I_{INJ}) will flow if an overload current flows through an adjacent pin.
- 3) Not subject to production test, verified by design/characterization.
- 4) Not subject to production test, verified by design/characterization. However, for applications with strict low power-down current requirements, it is mandatory that no active voltage source is supplied at any GPIO pin when V_{DDP} is powered off.

3.2.2 Analog to Digital Converters (ADC)

Table 12 shows the Analog to Digital Converter (ADC) characteristics.

Table 12 ADC Characteristics (Operating Conditions apply)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Supply voltage range (internal reference)	V_{DD_int} SR	1.8	–	3.0	V	SHSCFG.AREF = 11 _B
		3.0	–	5.5	V	SHSCFG.AREF = 10 _B
Supply voltage range (external reference)	V_{DD_ext} SR	3.0	–	5.5	V	SHSCFG.AREF = 00 _B
Analog input voltage range	V_{AIN} SR	$V_{SSP} - 0.05$	–	$V_{DDP} + 0.05$	V	
Auxiliary analog reference ground (SH0-CH0, SH1-CH0)	V_{REFGND} SR	$V_{SSP} - 0.05$	–	$V_{DDP} + 0.05$	V	
Internal reference voltage (full scale value)	V_{REFINT} CC	4.82	5	5.18	V	-40°C - 105°C
		4.9	5	5.1	V	0°C - 85°C ¹⁾
Switched capacitance of an analog input ¹⁾	C_{AINS} CC	–	1.2	2	pF	GNCTRxz.GAINy = 00 _B (unity gain)
		–	1.2	2	pF	GNCTRxz.GAINy = 01 _B (gain g1)
		–	4.5	6	pF	GNCTRxz.GAINy = 10 _B (gain g2)
		–	4.5	6	pF	GNCTRxz.GAINy = 11 _B (gain g3)
Total capacitance of an analog input	C_{AINT} CC	–	–	10	pF	¹⁾
Total capacitance of the reference input	C_{AREFT} CC	–	–	10	pF	¹⁾

Electrical Parameter
Table 12 ADC Characteristics (Operating Conditions apply) (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Gain settings	G_{IN} CC	1			–	GNCTRxz.GAINy = 00 _B (unity gain)
		3			–	GNCTRxz.GAINy = 01 _B (gain g1)
		6			–	GNCTRxz.GAINy = 10 _B (gain g2)
		12			–	GNCTRxz.GAINy = 11 _B (gain g3)
Sample Time	t_{sample} CC	3	–	–	1 / f_{ADC}	$V_{DDP} = 5.0$ V
		3	–	–	1 / f_{ADC}	$V_{DDP} = 3.3$ V
		30	–	–	1 / f_{ADC}	$V_{DDP} = 1.8$ V
Sigma delta loop hold time	t_{SD_hold} CC	20	–	–	μs	Residual charge stored in an active sigma delta loop remains available
Conversion time in fast compare mode	t_{CF} CC	9			1 / f_{ADC}	²⁾
Conversion time in 12-bit mode	t_{C12} CC	20			1 / f_{ADC}	²⁾
Maximum sample rate in 12-bit mode ³⁾	f_{C12} CC	–	–	$f_{ADC} / 42.5$	–	1 sample pending
		–	–	$f_{ADC} / 62.5$	–	2 samples pending
Conversion time in 10-bit mode	t_{C10} CC	18			1 / f_{ADC}	²⁾
Maximum sample rate in 10-bit mode ³⁾	f_{C10} CC	–	–	$f_{ADC} / 40.5$	–	1 sample pending
		–	–	$f_{ADC} / 58.5$	–	2 samples pending
Conversion time in 8-bit mode	t_{C8} CC	16			1 / f_{ADC}	²⁾

Electrical Parameter
Table 12 ADC Characteristics (Operating Conditions apply) (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Maximum sample rate in 8-bit mode ³⁾	f_{C8} CC	–	–	$f_{ADC} / 38.5$	–	1 sample pending
		–	–	$f_{ADC} / 54.5$	–	2 samples pending
DNL error	EA_{DNL} CC	–	±2.0	–	LSB 12	
INL error	EA_{INL} CC	–	±4.0	–	LSB 12	
Gain error with external reference	EA_{GAIN} CC	–	±0.5	–	%	SHSCFG.AREF = 00 _B (calibrated)
Gain error with internal reference	EA_{GAIN} CC	–	±3.6	–	%	SHSCFG.AREF = 1X _B (calibrated), -40°C - 105°C
		–	±2.0	–	%	SHSCFG.AREF = 1X _B (calibrated), 0°C - 85°C
Offset error	EA_{OFF} CC	–	±6.0	–	LSB 12	Calibrated

1) Not subject to production test, verified by design/characterization.

2) No pending samples assumed, excluding sampling time and calibration.

3) Includes synchronization and calibration (average of gain and offset calibration).

3.3.2 Output Rise/Fall Times

Table 19 provides the characteristics of the output rise/fall times in the XMC1300. **Figure 10** describes the rise time and fall time parameters.

Table 19 Output Rise/Fall Times Parameters (Operating Conditions apply)

Parameter	Symbol	Limit Values		Unit	Test Conditions
		Min.	Max.		
Rise/fall times on High Current Pad ¹⁾²⁾	$t_{\text{HCPR}}, t_{\text{HCPF}}$	—	9	ns	50 pF @ 5 V ³⁾
		—	12	ns	50 pF @ 3.3 V ⁴⁾
		—	25	ns	50 pF @ 1.8 V ⁵⁾
Rise/fall times on Standard Pad ¹⁾²⁾	$t_{\text{R}}, t_{\text{F}}$	—	12	ns	50 pF @ 5 V ⁶⁾
		—	15	ns	50 pF @ 3.3 V ⁷⁾
		—	31	ns	50 pF @ 1.8 V ⁸⁾

1) Rise/Fall time parameters are taken with 10% - 90% of supply.

2) Not all parameters are 100% tested, but are verified by design/characterisation and test correlation.

3) Additional rise/fall time valid for $C_L = 50 \text{ pF} - C_L = 100 \text{ pF}$ @ 0.150 ns/pF at 5 V supply voltage.

4) Additional rise/fall time valid for $C_L = 50 \text{ pF} - C_L = 100 \text{ pF}$ @ 0.205 ns/pF at 3.3 V supply voltage.

5) Additional rise/fall time valid for $C_L = 50 \text{ pF} - C_L = 100 \text{ pF}$ @ 0.445 ns/pF at 1.8 V supply voltage.

6) Additional rise/fall time valid for $C_L = 50 \text{ pF} - C_L = 100 \text{ pF}$ @ 0.225 ns/pF at 5 V supply voltage.

7) Additional rise/fall time valid for $C_L = 50 \text{ pF} - C_L = 100 \text{ pF}$ @ 0.288 ns/pF at 3.3 V supply voltage.

8) Additional rise/fall time valid for $C_L = 50 \text{ pF} - C_L = 100 \text{ pF}$ @ 0.588 ns/pF at 1.8 V supply voltage.

3.3.5 Serial Wire Debug Port (SW-DP) Timing

The following parameters are applicable for communication through the SW-DP interface.

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 23 SWD Interface Timing Parameters(Operating Conditions apply)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
SWDCLK high time	t_1 SR	50	—	500000	ns	—
SWDCLK low time	t_2 SR	50	—	500000	ns	—
SWDIO input setup to SWDCLK rising edge	t_3 SR	10	—	—	ns	—
SWDIO input hold after SWDCLK rising edge	t_4 SR	10	—	—	ns	—
SWDIO output valid time after SWDCLK rising edge	t_5 CC	—	—	68	ns	$C_L = 50$ pF
		—	—	62	ns	$C_L = 30$ pF
SWDIO output hold time from SWDCLK rising edge	t_6 CC	4	—	—	ns	

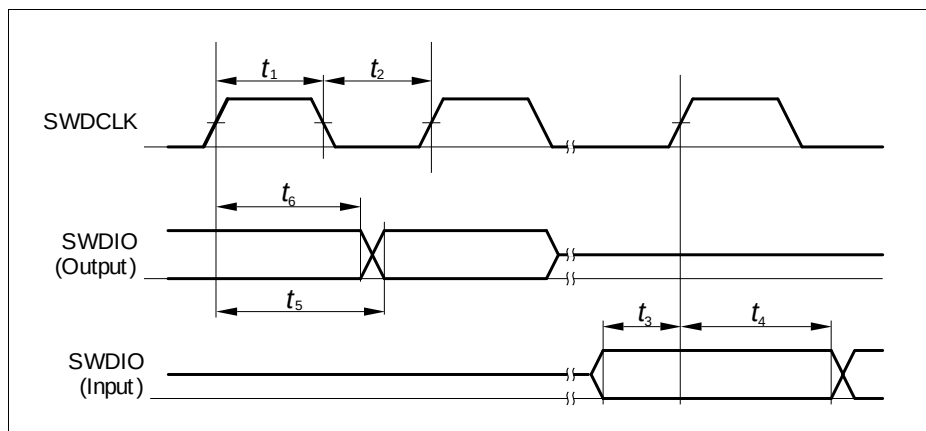


Figure 15 SWD Timing

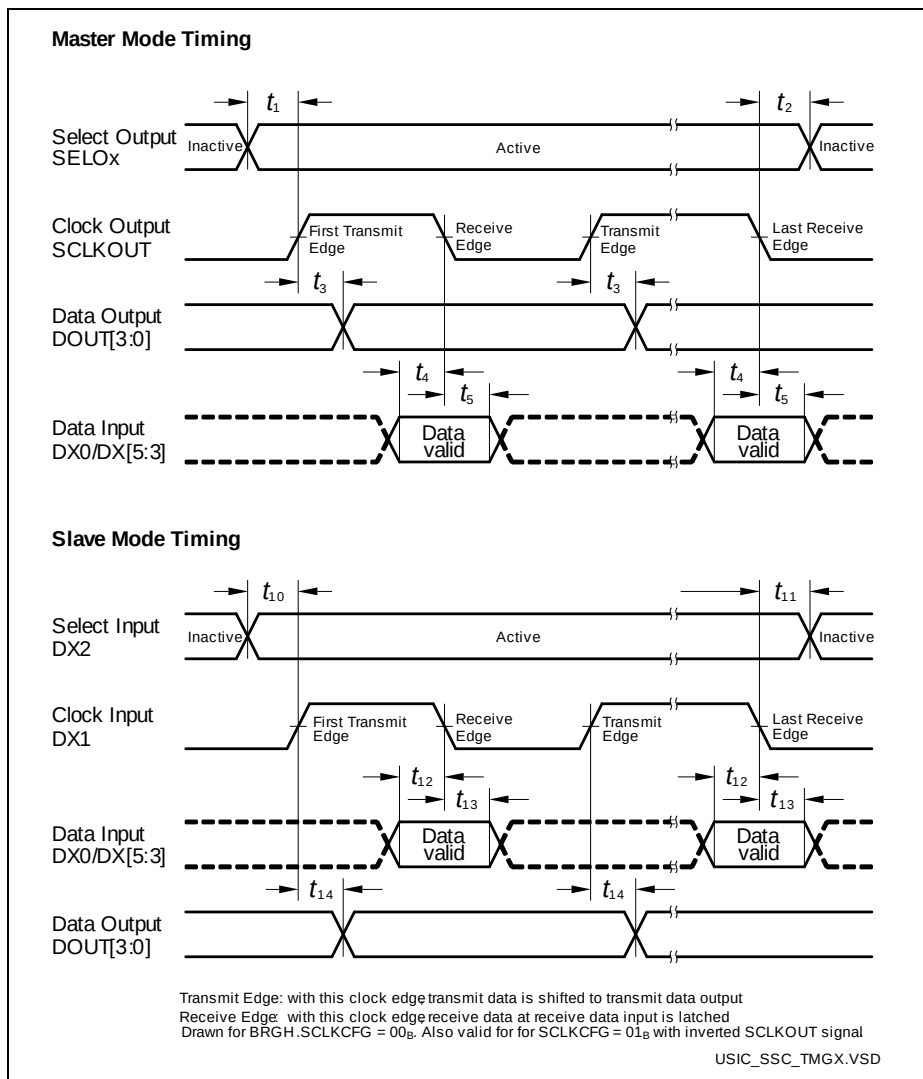


Figure 16 USIC - SSC Master/Slave Mode Timing

Note: This timing diagram shows a standard configuration, for which the slave select signal is low-active, and the serial clock signal is not shifted and not inverted.

Table 28 USIC IIC Fast Mode Timing ¹⁾

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Fall time of both SDA and SCL	t_1 CC/SR	20 + 0.1 * C _b ²⁾	-	300	ns	
Rise time of both SDA and SCL	t_2 CC/SR	20 + 0.1 * C _b	-	300	ns	
Data hold time	t_3 CC/SR	0	-	-	µs	
Data set-up time	t_4 CC/SR	100	-	-	ns	
LOW period of SCL clock	t_5 CC/SR	1.3	-	-	µs	
HIGH period of SCL clock	t_6 CC/SR	0.6	-	-	µs	
Hold time for (repeated) START condition	t_7 CC/SR	0.6	-	-	µs	
Set-up time for repeated START condition	t_8 CC/SR	0.6	-	-	µs	
Set-up time for STOP condition	t_9 CC/SR	0.6	-	-	µs	
Bus free time between a STOP and START condition	t_{10} CC/SR	1.3	-	-	µs	
Capacitive load for each bus line	C _b SR	-	-	400	pF	

1) Due to the wired-AND configuration of an IIC bus system, the port drivers of the SCL and SDA signal lines need to operate in open-drain mode. The high level on these lines must be held by an external pull-up device, approximately 10 kOhm for operation at 100 kbit/s, approximately 2 kOhm for operation at 400 kbit/s.

2) C_b refers to the total capacitance of one bus line in pF.

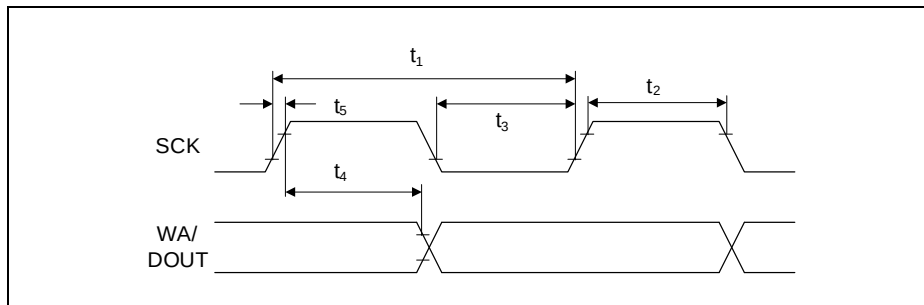


Figure 18 USIC IIS Master Transmitter Timing

Table 30 USIC IIS Slave Receiver Timing

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Clock period	t_6 SR	$4/f_{MCLK}$	-	-	ns	
Clock HIGH	t_7 SR	$0.35 \times t_{6min}$	-	-	ns	
Clock Low	t_8 SR	$0.35 \times t_{6min}$	-	-	ns	
Set-up time	t_9 SR	$0.2 \times t_{6min}$	-	-	ns	
Hold time	t_{10} SR	10	-	-	ns	

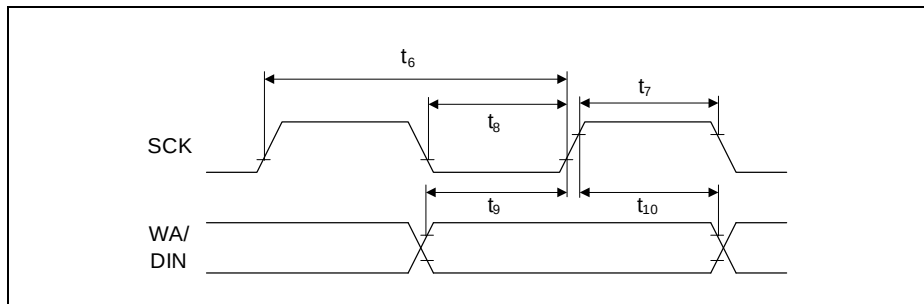


Figure 19 USIC IIS Slave Receiver Timing

The internal power consumption is defined as

$$P_{\text{INT}} = V_{\text{DDP}} \times I_{\text{DDP}} \text{ (switching current and leakage current).}$$

The static external power consumption caused by the output drivers is defined as

$$P_{\text{IOSTAT}} = \Sigma((V_{\text{DDP}} - V_{\text{OH}}) \times I_{\text{OH}}) + \Sigma(V_{\text{OL}} \times I_{\text{OL}})$$

The dynamic external power consumption caused by the output drivers (P_{IODYN}) depends on the capacitive load connected to the respective pins and their switching frequencies.

If the total power dissipation for a given system configuration exceeds the defined limit, countermeasures must be taken to ensure proper system operation:

- Reduce V_{DDP} , if possible in the system
- Reduce the system frequency
- Reduce the number of output pins
- Reduce the load on active output drivers

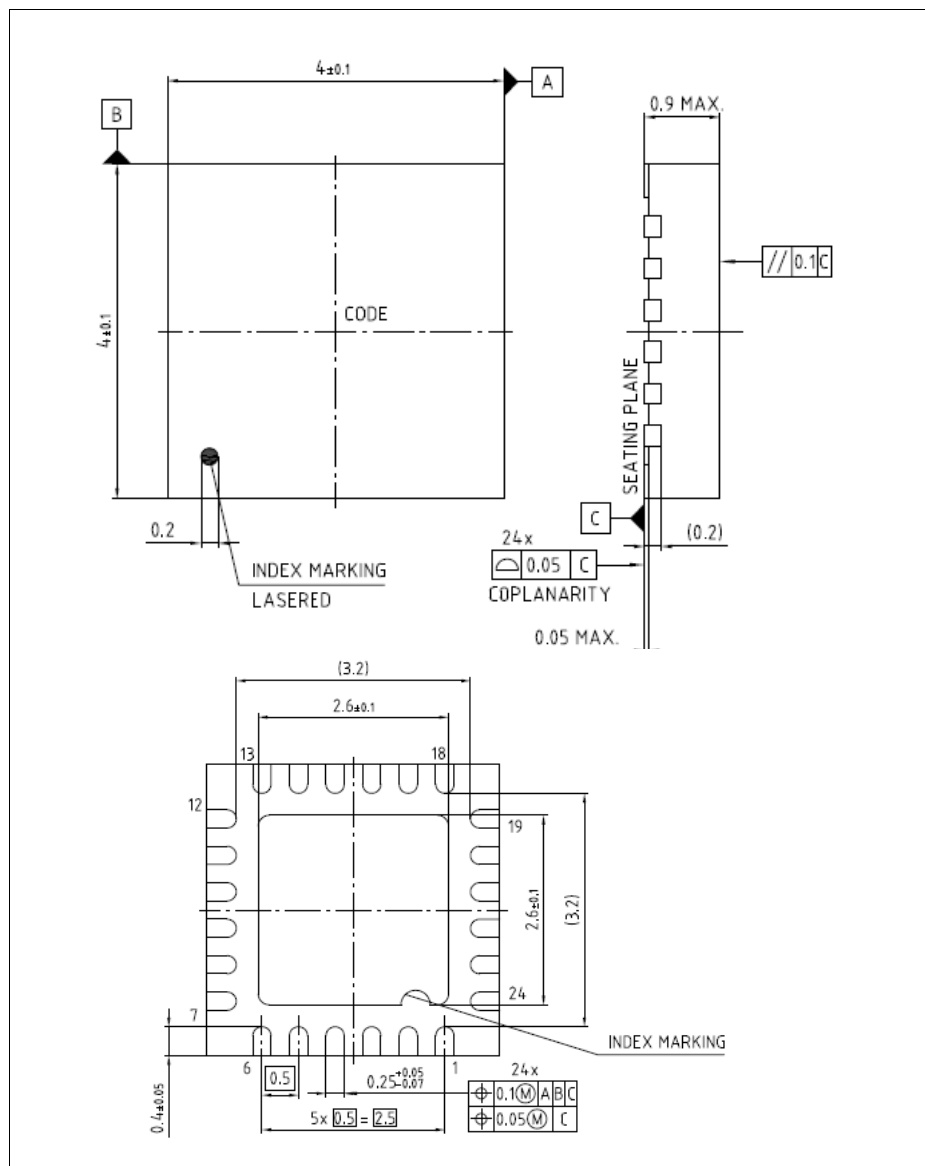


Figure 22 PG-VQFN-24-19